

IN THE CLAIMS:

- Sub C1*
1. (Twice Amended) A probe apparatus for testing a circuit chip, said probe
apparatus comprising a probe group having two or more probes within a guiding
boundary for independently conductively contacting a single terminal of said
circuit chip and allowing a test path resistance be measured without affecting said
circuit chip.

- B1*
- Sub C2*
2. (Amended) The probe apparatus of claim 1, further comprising an electronic circuit
capable of recognizing said test path resistance and correspondingly compensating a
voltage drop of an operational signal passing through at least one of said probes.